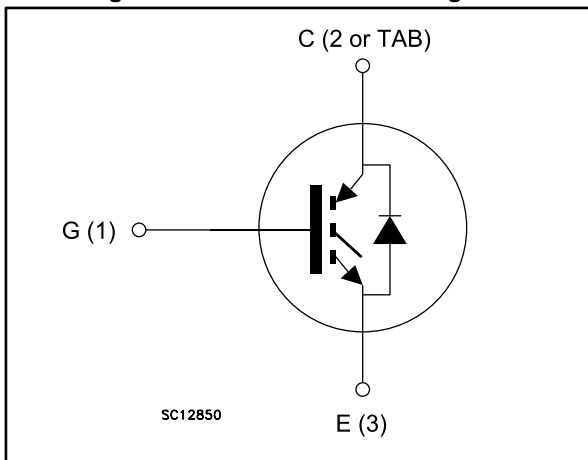


Trench gate field-stop IGBT, M series 650 V, 4 A low loss

Datasheet - production data



Figure 1: Internal schematic diagram



Features

- 6 μ s of short-circuit withstand time
- $V_{CE(sat)} = 1.6$ V (typ.) @ $I_C = 4$ A
- Tight parameter distribution
- Safer paralleling
- Low thermal resistance
- Soft and very fast recovery antiparallel diode

Applications

- Motor control
- UPS
- PFC

Description

This device is an IGBT developed using an advanced proprietary trench gate field-stop structure. The device is part of the M series IGBTs, which represent an optimal balance between inverter system performance and efficiency where low-loss and short-circuit functionality are essential. Furthermore, the positive $V_{CE(sat)}$ temperature coefficient and tight parameter distribution result in safer paralleling operation.

Table 1: Device summary

Order code	Marking	Package	Packing
STGP4M65DF2	G4M65DF2	TO-220	Tube

Contents

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1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{CES}	Collector-emitter voltage ($V_{GE} = 0$ V)	650	V
I_C	Continuous collector current at $T_C = 25$ °C	8	A
	Continuous collector current at $T_C = 100$ °C	4	A
$I_{CP}^{(1)}$	Pulsed collector current	16	A
V_{GE}	Gate-emitter voltage	± 20	V
I_F	Continuous forward current at $T_C = 25$ °C	8	A
	Continuous forward current at $T_C = 100$ °C	4	A
$I_{FP}^{(1)}$	Pulsed forward current	16	A
P_{TOT}	Total dissipation at $T_C = 25$ °C	68	W
T_{STG}	Storage temperature range	- 55 to 150	°C
T_J	Operating junction temperature range	- 55 to 175	°C

Notes:

⁽¹⁾Pulse width limited by maximum junction temperature.

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance junction-case IGBT	2.2	°C/W
R_{thJC}	Thermal resistance junction-case diode	5	°C/W
R_{thJA}	Thermal resistance junction-ambient	62.5	°C/W

2 Electrical characteristics

$T_C = 25\text{ °C}$ unless otherwise specified

Table 4: Static characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)CES}$	Collector-emitter breakdown voltage	$V_{GE} = 0\text{ V}$, $I_C = 250\text{ }\mu\text{A}$	650			V
$V_{CE(sat)}$	Collector-emitter saturation voltage	$V_{GE} = 15\text{ V}$, $I_C = 4\text{ A}$		1.6	2.1	V
		$V_{GE} = 15\text{ V}$, $I_C = 4\text{ A}$, $T_J = 125\text{ °C}$		1.9		
		$V_{GE} = 15\text{ V}$, $I_C = 4\text{ A}$, $T_J = 175\text{ °C}$		2.1		
V_F	Forward on-voltage	$I_F = 4\text{ A}$		1.9		V
		$I_F = 4\text{ A}$, $T_J = 125\text{ °C}$		1.7		
		$I_F = 4\text{ A}$, $T_J = 175\text{ °C}$		1.6		
$V_{GE(th)}$	Gate threshold voltage	$V_{CE} = V_{GE}$, $I_C = 250\text{ }\mu\text{A}$	5	6	7	V
I_{CES}	Collector cut-off current	$V_{GE} = 0\text{ V}$, $V_{CE} = 650\text{ V}$			25	μA
I_{GES}	Gate-emitter leakage current	$V_{CE} = 0\text{ V}$, $V_{GE} = \pm 20\text{ V}$			± 250	μA

Table 5: Dynamic characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{ies}	Input capacitance	$V_{CE} = 25\text{ V}$, $f = 1\text{ MHz}$, $V_{GE} = 0\text{ V}$	-	369	-	pF
C_{oes}	Output capacitance		-	24.8	-	
C_{res}	Reverse transfer capacitance		-	8	-	
Q_g	Total gate charge	$V_{CC} = 520\text{ V}$, $I_C = 4\text{ A}$, $V_{GE} = 15\text{ V}$ (see Figure 30: "Gate charge test circuit")	-	15.2	-	nC
Q_{ge}	Gate-emitter charge		-	3	-	
Q_{gc}	Gate-collector charge		-	7	-	

Table 6: IGBT switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{CE} = 400\text{ V}$, $I_C = 4\text{ A}$, $V_{GE} = 15\text{ V}$, $R_G = 47\ \Omega$ (see Figure 29: "Test circuit for inductive load switching")		12	-	ns
t_r	Current rise time			6.9	-	ns
$(di/dt)_{on}$	Turn-on current slope			480	-	A/ μ s
$t_{d(off)}$	Turn-off-delay time			86	-	ns
t_f	Current fall time			120	-	ns
$E_{on}^{(1)}$	Turn-on switching energy			0.040	-	mJ
$E_{off}^{(2)}$	Turn-off switching energy			0.136	-	mJ
E_{ts}	Total switching energy			0.176	-	mJ
$t_{d(on)}$	Turn-on delay time	$V_{CE} = 400\text{ V}$, $I_C = 4\text{ A}$, $V_{GE} = 15\text{ V}$, $R_G = 47\ \Omega$, $T_J = 175\text{ }^\circ\text{C}$ (see Figure 29: "Test circuit for inductive load switching")		11.6	-	ns
t_r	Current rise time			8	-	ns
$(di/dt)_{on}$	Turn-on current slope			410	-	A/ μ s
$t_{d(off)}$	Turn-off-delay time			85	-	ns
t_f	Current fall time			211	-	ns
$E_{on}^{(1)}$	Turn-on switching energy			0.067	-	mJ
$E_{off}^{(2)}$	Turn-off switching energy			0.210	-	mJ
E_{ts}	Total switching energy			0.277	-	mJ
t_{sc}	Short-circuit withstand time	$V_{CC} \leq 400\text{ V}$, $V_{GE} = 15\text{ V}$, $T_{Jstart} = 150\text{ }^\circ\text{C}$	6		-	μ s
		$V_{CC} \leq 400\text{ V}$, $V_{GE} = 13\text{ V}$, $T_{Jstart} = 150\text{ }^\circ\text{C}$	10		-	μ s

Notes:

(1)Including the reverse recovery of the diode.

(2)Including the tail of the collector current.

Table 7: Diode switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
t_{rr}	Reverse recovery time	$I_F = 4\text{ A}$, $V_R = 400\text{ V}$, $V_{GE} = 15\text{ V}$, $di/dt = 800\text{ A}/\mu\text{s}$ (see Figure 29: "Test circuit for inductive load switching")	-	133	-	ns
Q_{rr}	Reverse recovery charge		-	140	-	nC
I_{rrm}	Reverse recovery current		-	5	-	A
dl_{rr}/dt	Peak rate of fall of reverse recovery current during t_b		-	520	-	A/ μ s
E_{rr}	Reverse recovery energy		-	15	-	μ J
t_{rr}	Reverse recovery time		$I_F = 4\text{ A}$, $V_R = 400\text{ V}$, $V_{GE} = 15\text{ V}$, $T_J = 175\text{ }^\circ\text{C}$, $di/dt = 800\text{ A}/\mu\text{s}$ (see Figure 29: "Test circuit for inductive load switching")	-	236	-
Q_{rr}	Reverse recovery charge	-		370	-	nC
I_{rrm}	Reverse recovery current	-		6.6	-	A
dl_{rr}/dt	Peak rate of fall of reverse recovery current during t_b	-		378	-	A/ μ s
E_{rr}	Reverse recovery energy	-		32	-	μ J

2.1 Electrical characteristics (curves)

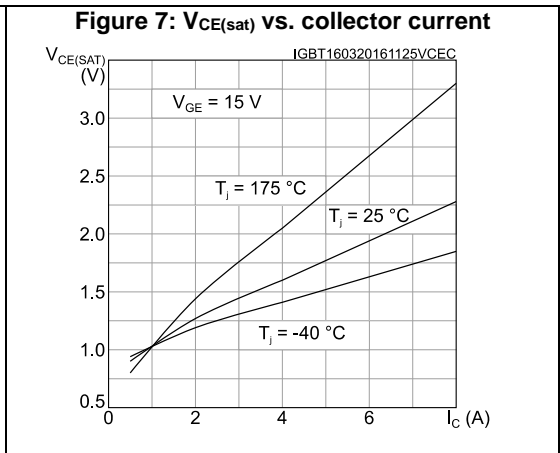
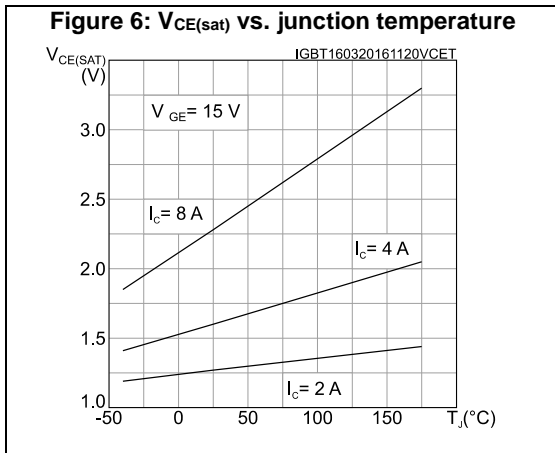
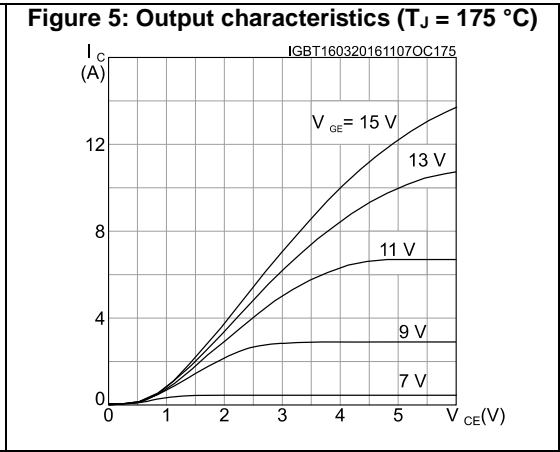
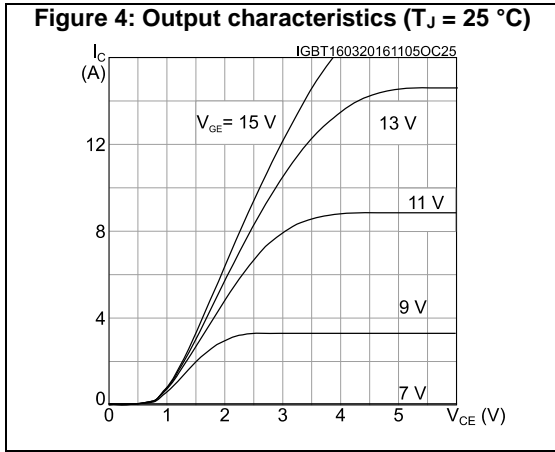
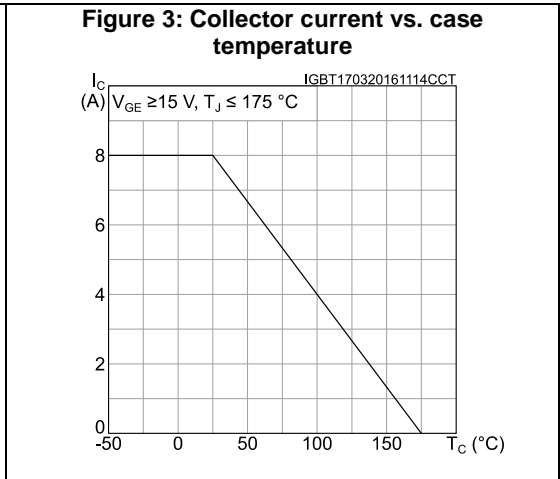
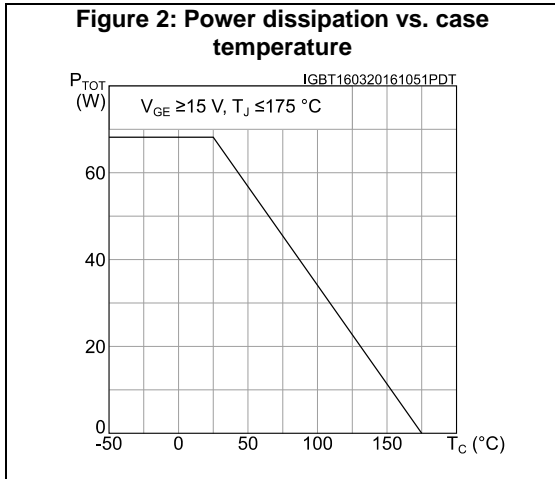


Figure 8: Collector current vs. switching frequency

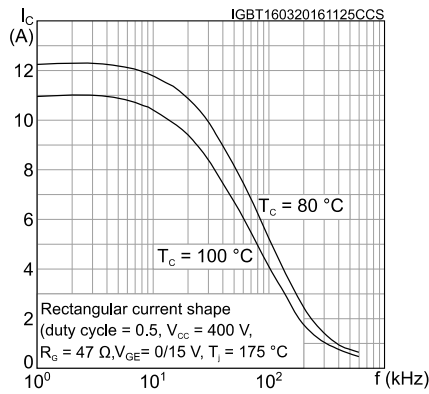


Figure 9: Forward bias safe operating area

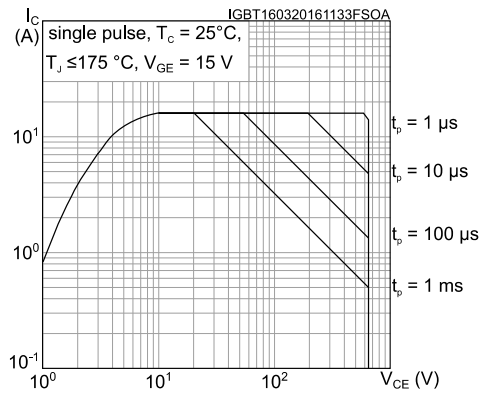


Figure 10: Transfer characteristics

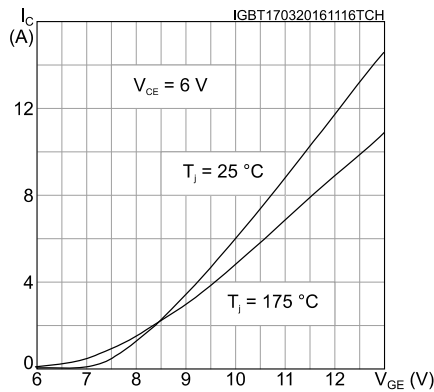


Figure 11: Diode VF vs. forward current

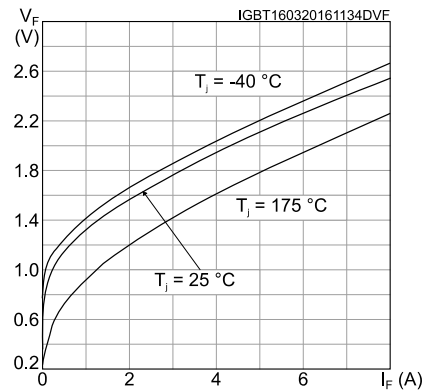


Figure 12: Normalized VGE(th) vs. junction temperature

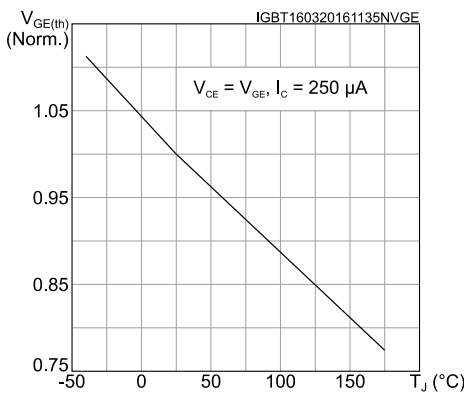
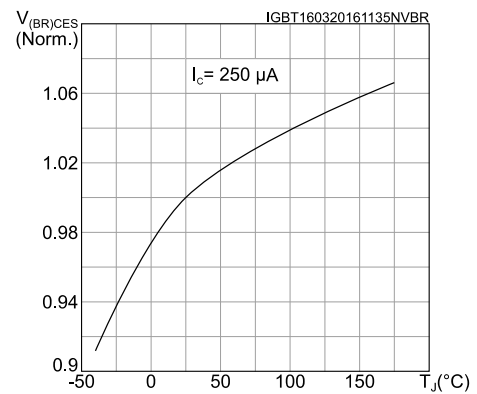


Figure 13: Normalized V(BR)CES vs. junction temperature



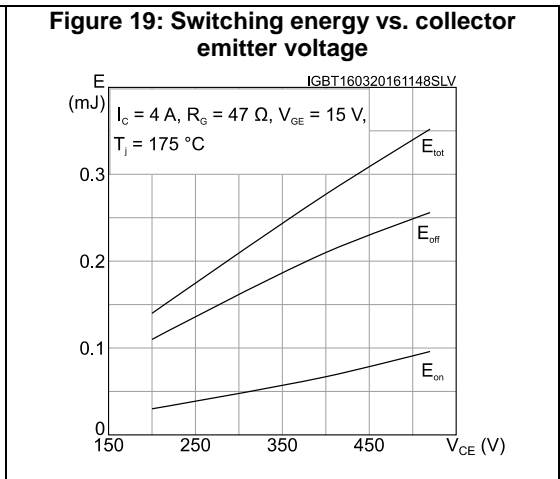
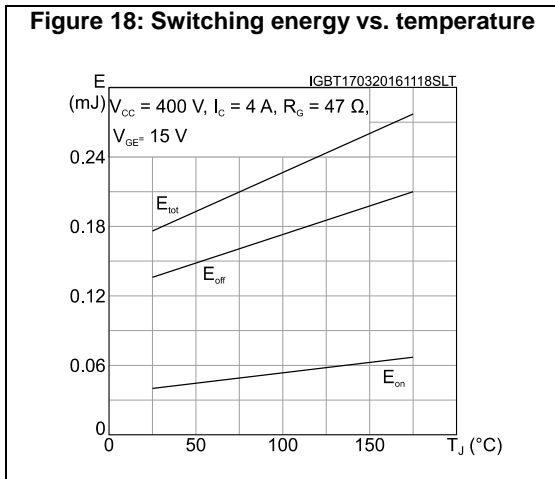
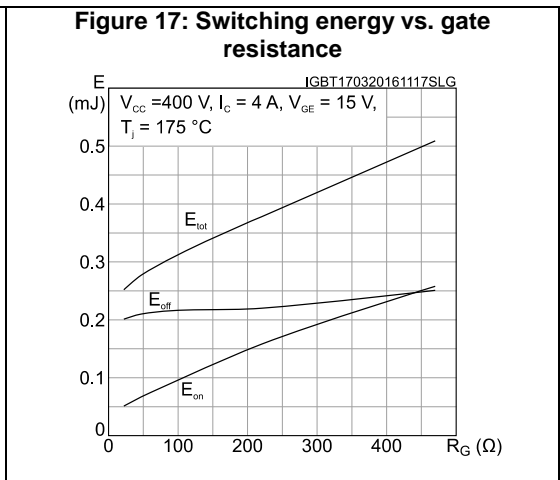
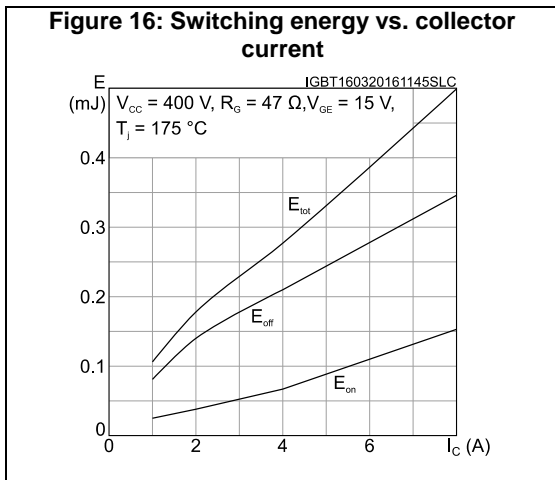
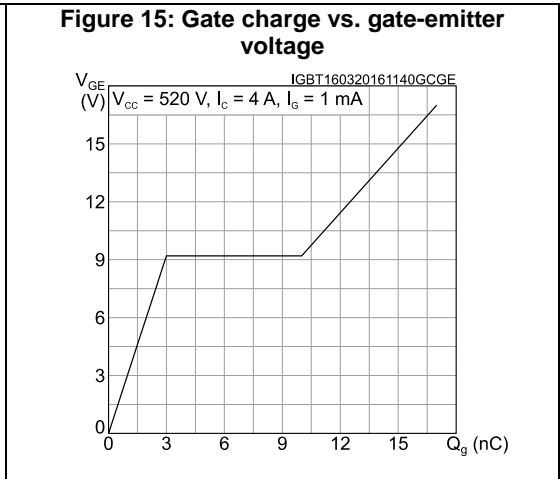
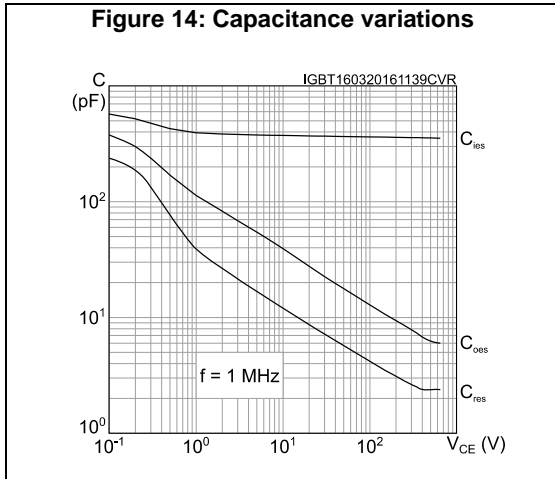


Figure 20: Short-circuit time and current vs. V_{GE}

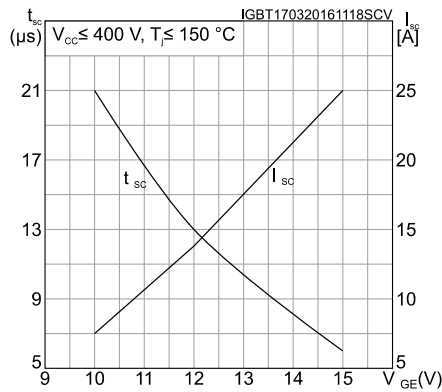


Figure 21: Switching times vs. collector current

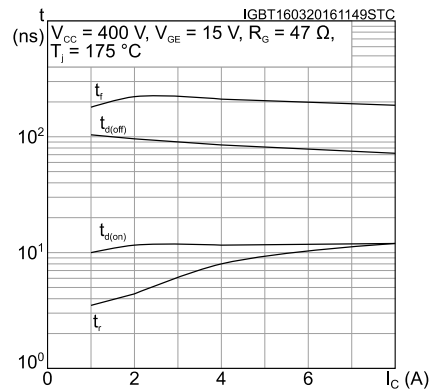


Figure 22: Switching times vs. gate resistance

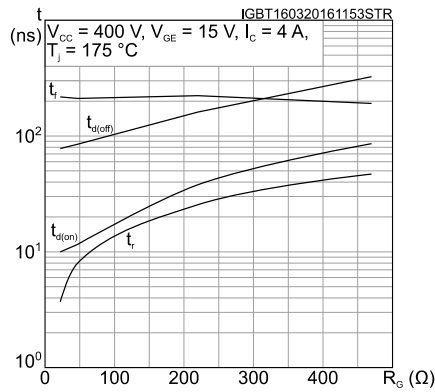


Figure 23: Reverse recovery current vs. diode current slope

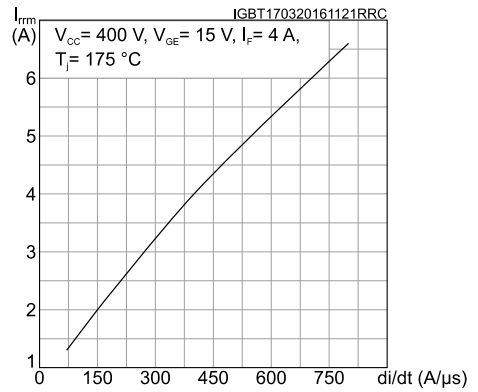


Figure 24: Reverse recovery time vs. diode current slope

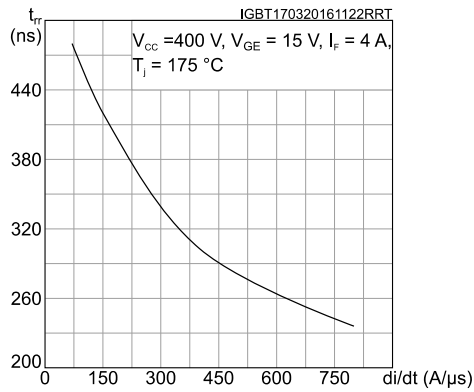


Figure 25: Reverse recovery charge vs. diode current slope

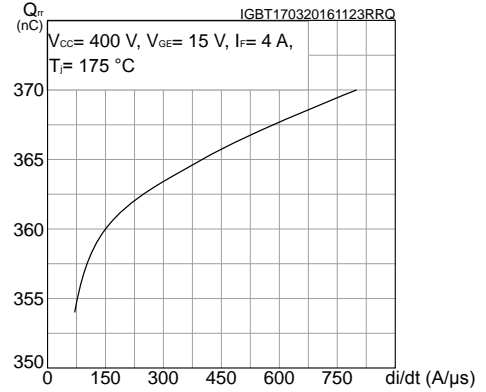


Figure 26: Reverse recovery energy vs. diode current slope

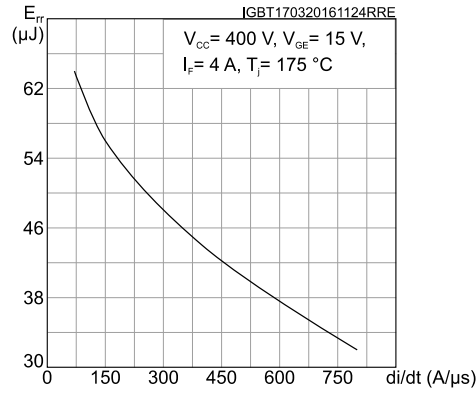


Figure 27: Thermal impedance for IGBT

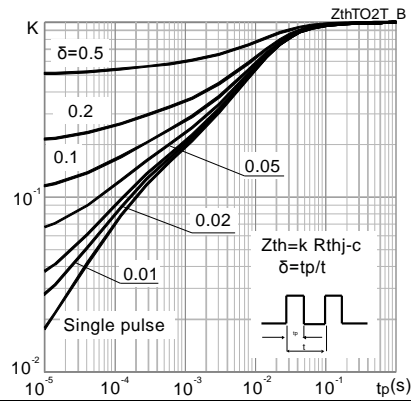
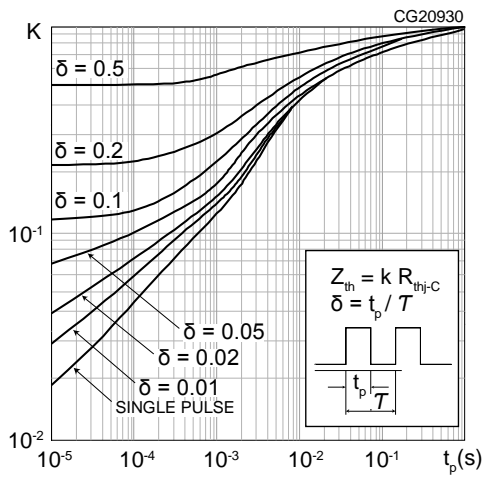
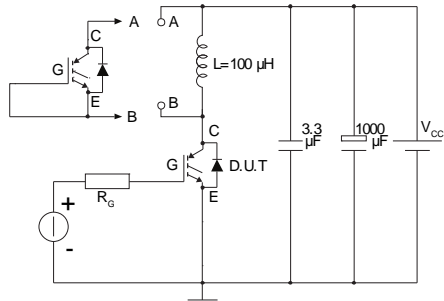


Figure 28: Thermal impedance for diode



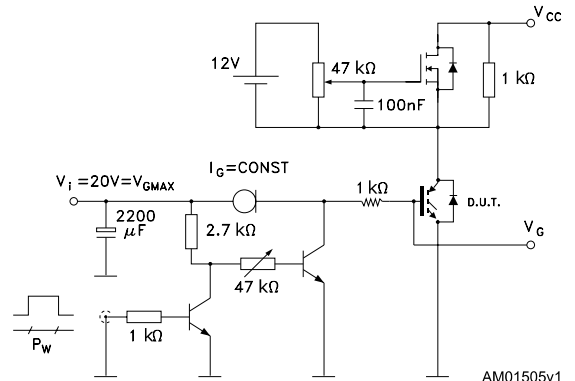
3 Test circuits

Figure 29: Test circuit for inductive load switching



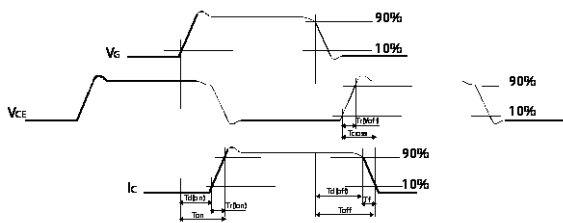
AM01504v1

Figure 30: Gate charge test circuit



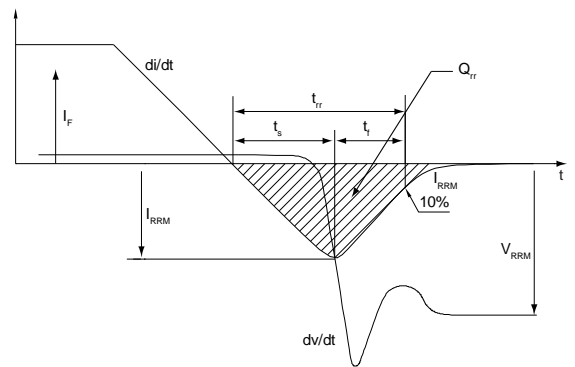
AM01505v1

Figure 31: Switching waveform



AM01506v1

Figure 32: Diode reverse recovery waveform



AM01507v1

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

4.1 TO-220 type A package information

Figure 33: TO-220 type A package outline

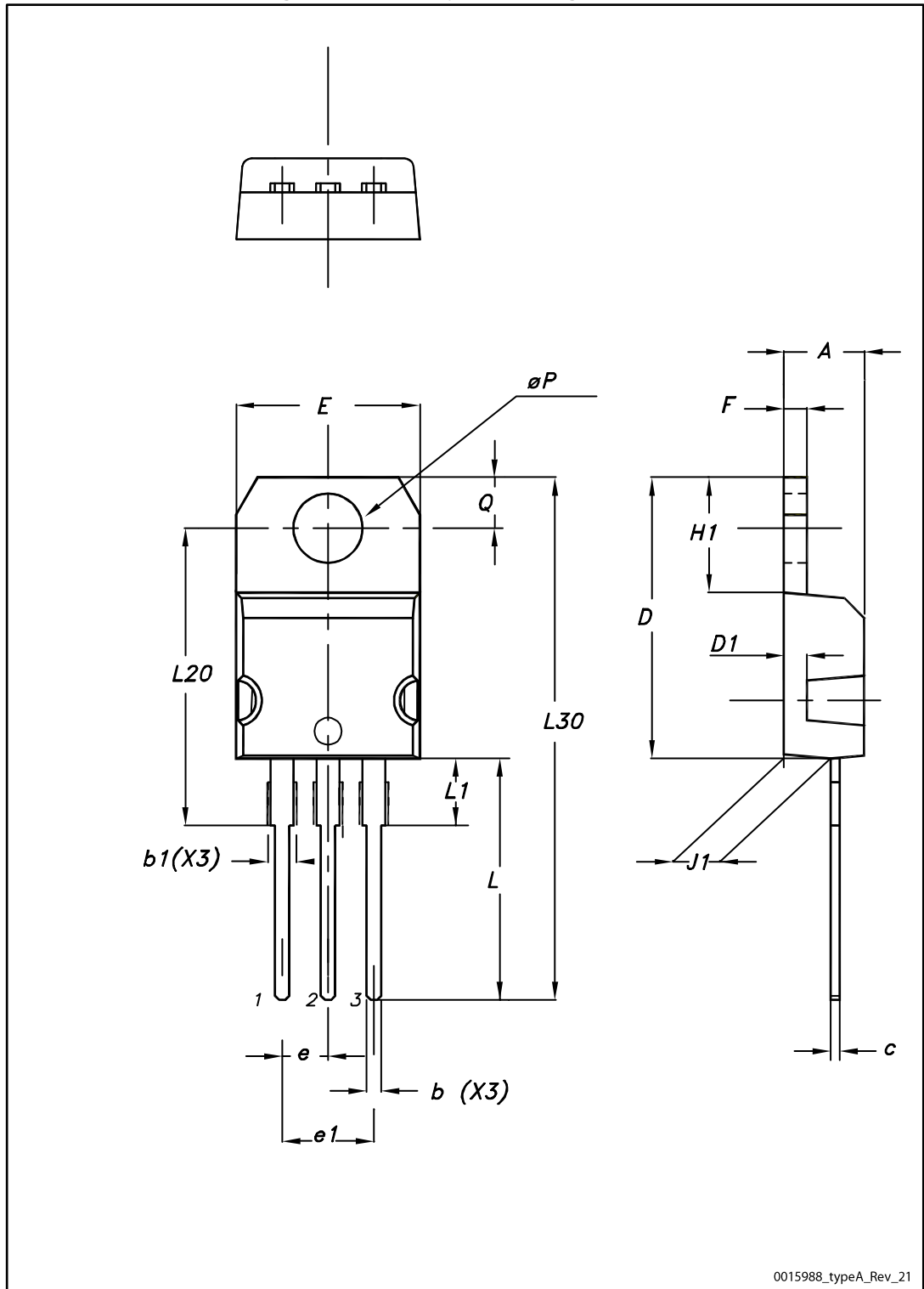


Table 8: TO-220 type A mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
b	0.61		0.88
b1	1.14		1.55
c	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10.00		10.40
e	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13.00		14.00
L1	3.50		3.93
L20		16.40	
L30		28.90	
øP	3.75		3.85
Q	2.65		2.95

5 Revision history

Table 9: Document revision history

Date	Revision	Changes
25-Nov-2015	1	First release.
30-Mar-2016	2	Modified: features in cover page Datasheet promoted from preliminary data to production data Modified: Table 2: " <i>Absolute maximum ratings</i> ", Table 4: " <i>Static characteristics</i> ", Table 5: " <i>Dynamic characteristics</i> ", Table 6: " <i>IGBT switching characteristics (inductive load)</i> " and Table 7: " <i>Diode switching characteristics (inductive load)</i> " Added: Section 2.1: " <i>Electrical characteristics (curves)</i> " Minor text changes
21-Nov-2016	3	Updated Table 2: "<i>Absolute maximum ratings</i>" Updated Table 6: "<i>IGBT switching characteristics (inductive load)</i>" Updated Figure 25: "<i>Reverse recovery charge vs. diode current slope</i>" Minor text changes

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